

# Gate-Level Timing Analysis

Smith Chapter 13

# Outline

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- ▶ Gate-delay models
- ▶ Circuit timing constraints
- ▶ After Synthesis:
  - ▶ VITAL models for gate-level simulation
  - ▶ VHDL netlist simulation with VITAL models and Standard Delay Format (SDF) files



# Logic cell delay models

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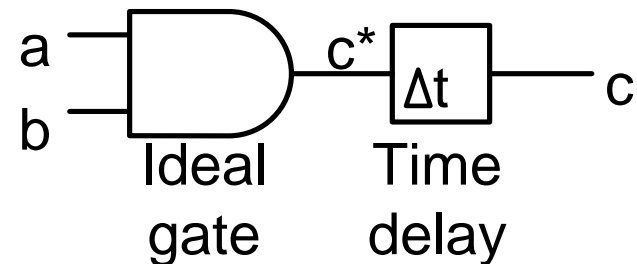
- ▶ “Delay” = time from the occurrence of an event until the occurrence time of a 2nd event caused by the first
  - ▶ depends on circuit structure & technology
  - ▶ may also depend on cell interconnects
  - ▶ model delays with different levels of detail/accuracy
  - ▶ may have a range of possible values (process/condition dependent)



# Primitive device delay models

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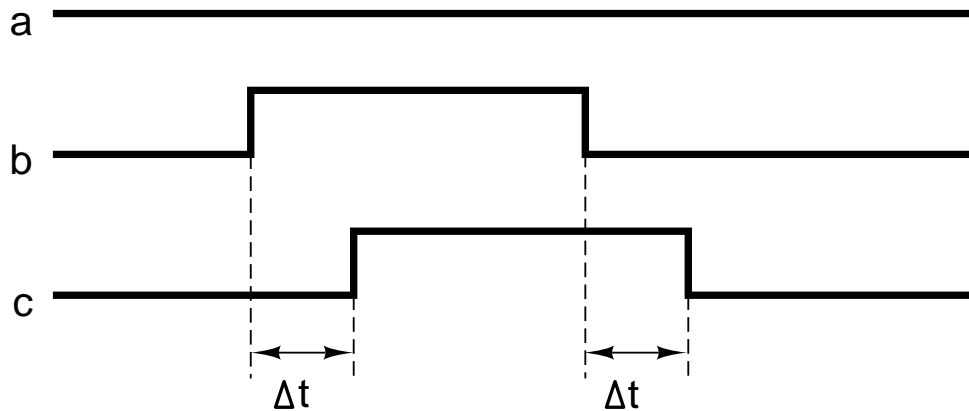
- ▶ A primitive logic gate has an intrinsic delay.
  - ▶ model as an ideal (zero-delay) gate and a “transport delay” element.
  - ▶ transport delay models:
    - ▶ unit/nominal delay
    - ▶ rise/fall delay
    - ▶ ambiguous or min/max delay



# Unit/nominal delay

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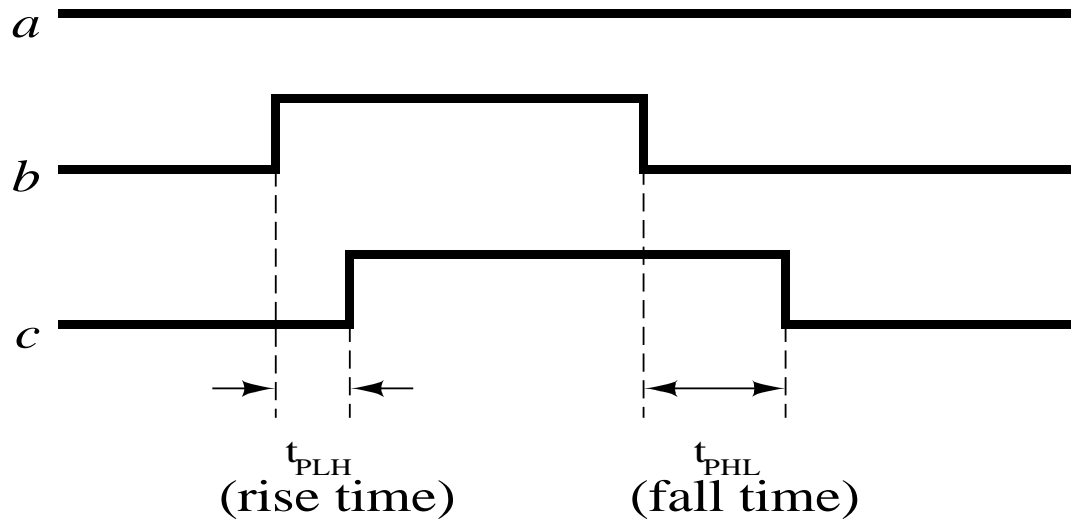
- ▶ Unit delay: each gate has delay of one “unit” of time.
- ▶ Nominal delay: delays determined separately for each type of gate  
(e.g., on time unit for NOR and two time units for XOR).



# Rise/fall delay

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- ▶ Delays for 0 to 1 and 1 to 0 transitions.
  - ▶  $t_{PLH}$  (rise time): propagation delay for signal changing from low to high.
  - ▶  $t_{PHL}$  (fall time): propagation delay from high to low.



# Example: ADK tsmc035 technology

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## ▶ nand02 cell:

- ▶  $t_P=0.537466$  (ns) INV on A0(RI) to Y(FA)
- ▶  $t_P=0.810693$  (ns) INV on A0(FA) to Y(RI)
- ▶  $t_P=0.421754$  (ns) INV on A1(RI) to Y(FA)
- ▶  $t_P=0.868593$  (ns) INV on A1(FA) to Y(RI)

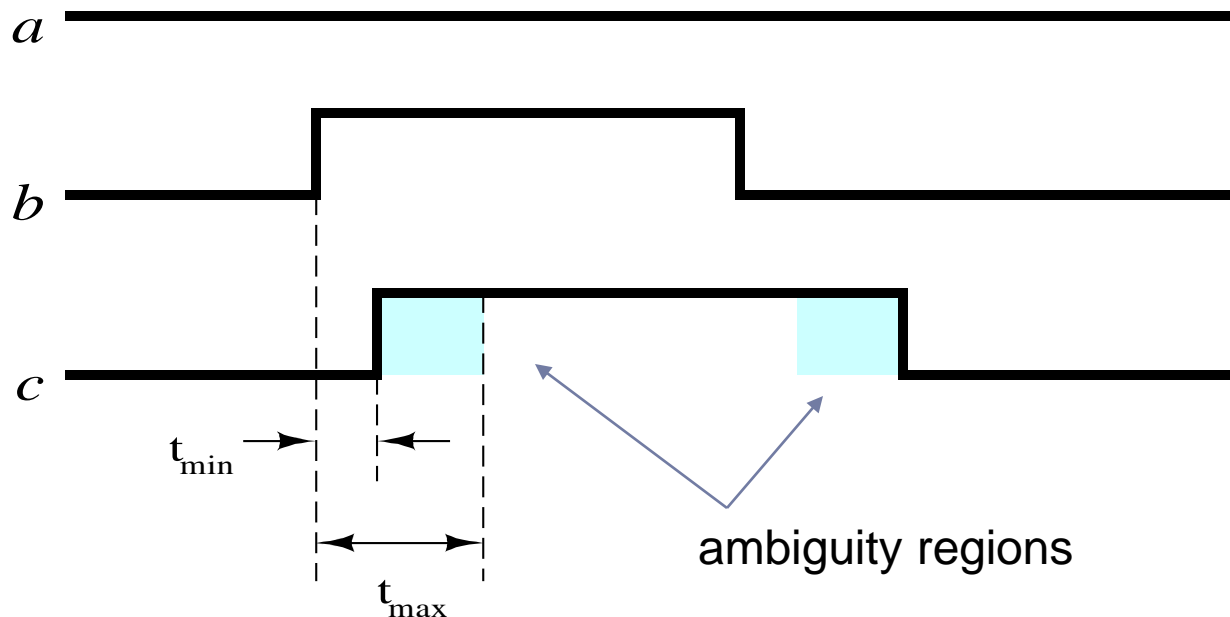
## ▶ and02 cell:

- ▶  $t_P=0.726188$  (ns) INV on A0(RI) to Y(FA)
  - ▶  $t_P=0.828392$  (ns) INV on A0(FA) to Y(RI)
  - ▶  $t_P=0.679021$  (ns) INV on A1(RI) to Y(FA)
  - ▶  $t_P=0.921874$  (ns) INV on A1(FA) to Y(RI)
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# Ambiguous or Min/Max Delay

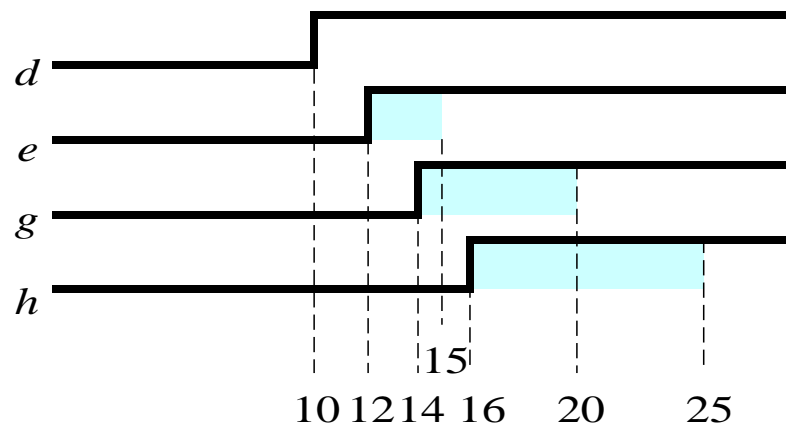
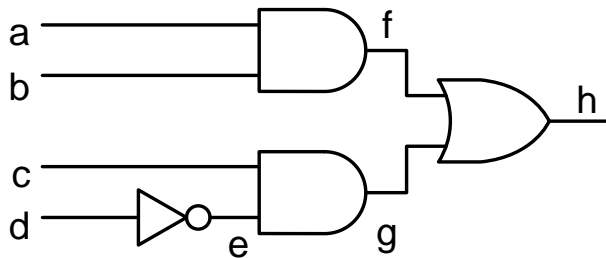
- ▶ Difficult to predict exact rise or fall time of a signal.
- ▶ For worst-case performance analysis,  $\{t_{min}, t_{max}\}$  is specified for each timing parameter.



# Accumulated min/max delays

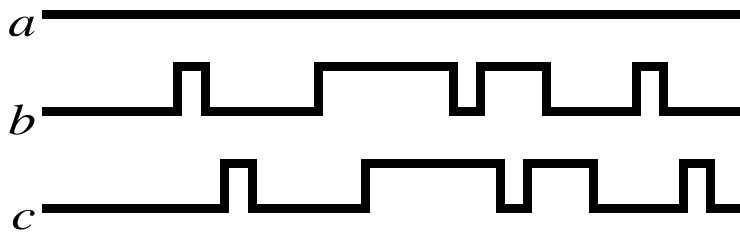
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- ▶ Simulation producing min/max delay results tend to be pessimistic.
  - ▶ ambiguity region larger at each level

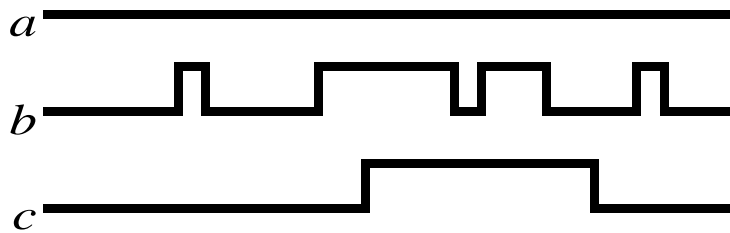


# Inertial Delay

- ▶ An input value must persist for some minimum duration of time to provide the output with the needed inertia to change.
- ▶ The minimum duration is called *inertial delay*.

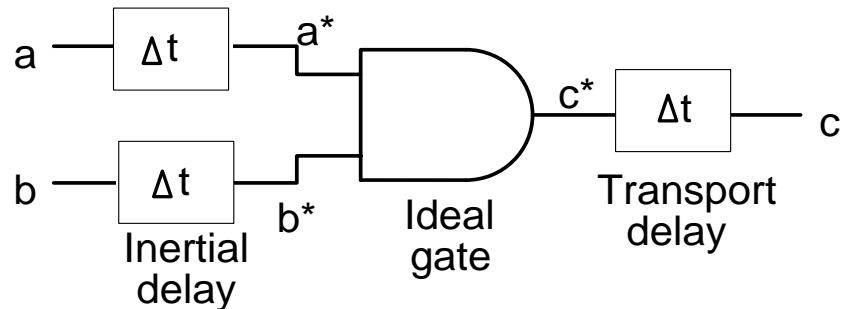


(a) Transport delay model



(b) Inertial delay model

Model with both inertial and transport delays:



# VHDL transport/inertial delays

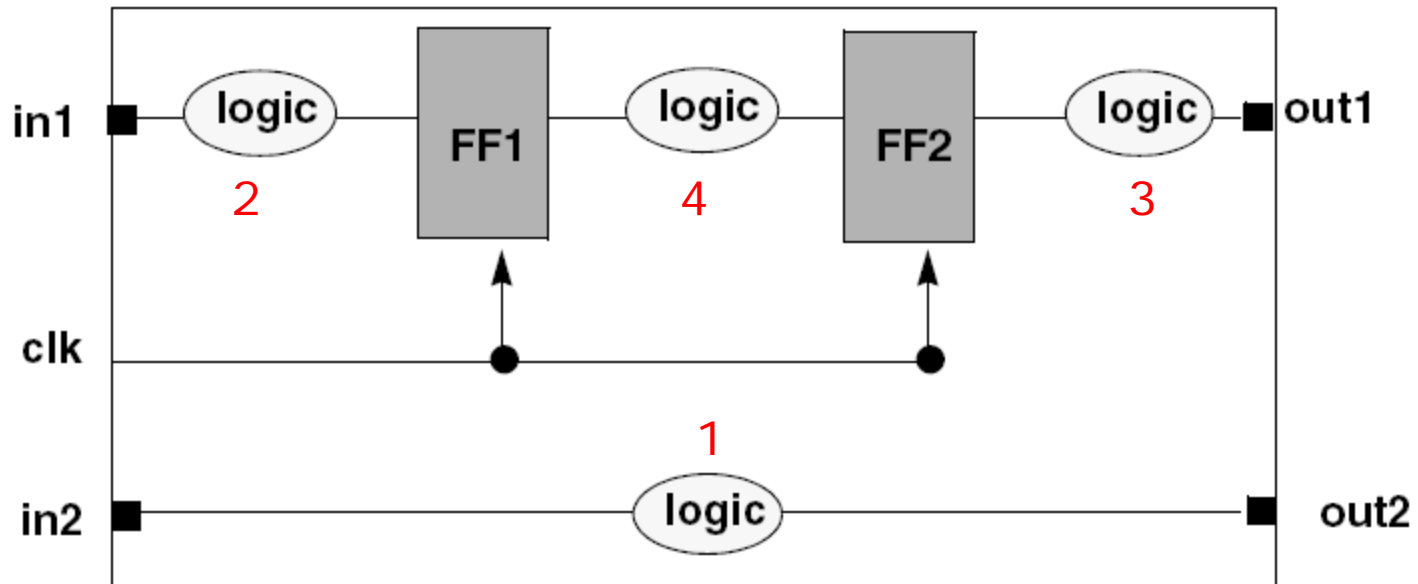
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- ▶ Default is “inertial” - reject pulses shorter than circuit switching time (cancel pending “events”)
    - ▶  $Op \leq Ip$  after 10 ns;
    - ▶  $Op \leq \text{inertial } Ip$  after 10 ns;
    - ▶  $Op \leq \text{reject 10 ns inertial } Ip$  after 10 ns;
  - ▶ “Transport” delay – transmit all pulses, of any duration
    - ▶  $Op \leq \text{transport } Ip$  after 10 ns;
    - ▶  $Op \leq \text{transport } Ip$  after 10 ns, not  $Ip$  after 20 ns
- Equivalent:
- ▶  $Op \leq \text{reject 0 ns inertial } Ip$  after 10 ns;
  - ▶  $Op \leq \text{reject 0 ns inertial } Ip$  after 10 ns, not  $Ip$  after 20 ns



# Path delays of interest

1. Combinational: primary input to primary output:  $in2 \rightarrow out2$
2. Primary input to register input:  $in1 \rightarrow FF1/D1$
3. Clock/register output to primary output:  $clk \rightarrow Q2 \rightarrow out1$
4. Clock/register output to register input:  $clk \rightarrow Q1 \rightarrow D2$

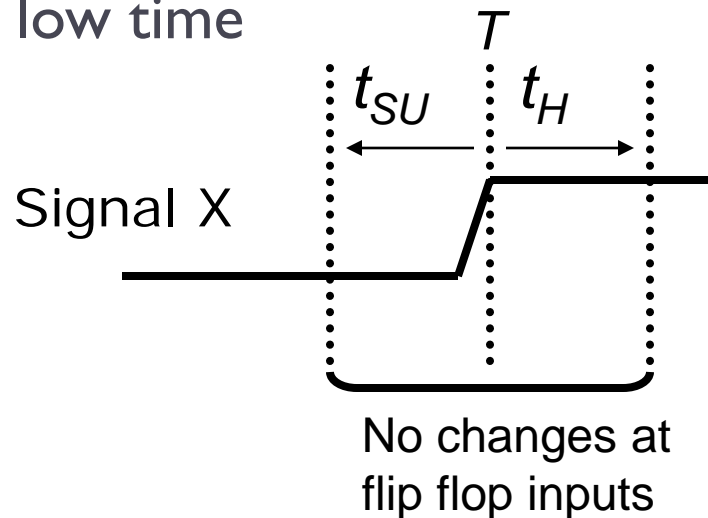


# Timing Constraints:

## Flip flop setup, hold & clock times

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- ▶ Constrain signal transitions to ensure reliable operation
  - ▶  **$t_{SU}$  (setup time)** of signal X with respect to signal Y = time prior to active change on Y by which X must be stable
  - ▶  **$t_H$  (hold time)** of signal X with respect to signal Y = time following active change on Y during which X must be stable
  - ▶  **$t_{PW}, t_H, t_L$**  = clock signal minimum pulse width, high time, low time

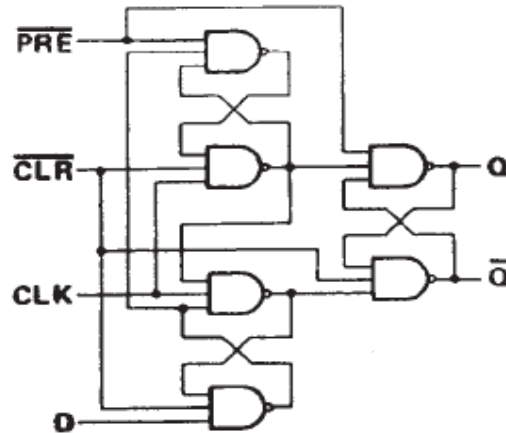


$T$  = time of clock transition

$t_{SU}$  = flip flop setup time

$t_H$  = flip flop hold time

# SN74LS74A (D flip flop) parameters



		SN54LS74A			SN74LS74A			UNIT	
		MIN	NOM	MAX	MIN	NOM	MAX		
$t_{\text{clock}}$	Clock frequency	0		25	0		25	MHz	
$t_w$	Pulse duration	CLK high		25	25		ns		
		PRE or CLR low		25	25				
$t_{\text{su}}$	Setup time-before CLK †	High-level data		20	20		ns		
		Low-level data		20	20				
$t_h$	Hold time-data after CLK †	5			5			ns	
PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS			MIN	TYP	MAX	UNIT
$f_{\text{max}}$			$R_L = 2 \text{ k}\Omega$ , $C_L = 15 \text{ pF}$			25	33		MHz
$t_{\text{PLH}}$	$\overline{\text{CLR}}$ , $\overline{\text{PRE}}$ or CLK	Q or $\overline{\text{Q}}$					13	25	ns
$t_{\text{PHL}}$							25	40	ns

Source: <http://focus.ti.com/lit/ds/symlink/sn74ls74a.pdf>

# ADK tsmc035 technology D flip flop

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## Report Timing Info for Instance /DFFR1 of TYPE QPT

tP = 0.637972 (ns) NONINV ON CLK(RI) TO Q(RI) --delays from CLK rise  
tP = 0.746466 (ns) INV ON CLK(RI) TO QB(FA)  
tP = 0.752151 (ns) INV ON CLK(RI) TO Q(FA)  
tP = 0.896604 (ns) NONINV ON CLK(RI) TO QB(RI)  
tP = 0.828865 (ns) INV ON R(RI) TO Q(FA) --delays from Reset active  
tP = 0.973914 (ns) NONINV ON R(RI) TO QB(RI)

tS = 0.688299 (ns) ON D(H) TO CLK(RI) -- setup times  
tS = 0.583595 (ns) ON D(L) TO CLK(RI)  
taS = 0.579838 (ns) ON R(FA) TO CLK(RI)

tH = -0.0942826 (ns) ON D(H) TO CLK(RI) -- hold times  
tH = -0.052878 (ns) ON D(L) TO CLK(RI)  
taH = 0.330582 (ns) ON R(FA) TO CLK(RI)

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# Methods for timing analysis

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## ▶ Timing simulation

- ▶ Primitive element models include delay and constraint parameters
  - ▶ Gate and/or transistor level
- ▶ Delays and constraint violations detected in simulation results

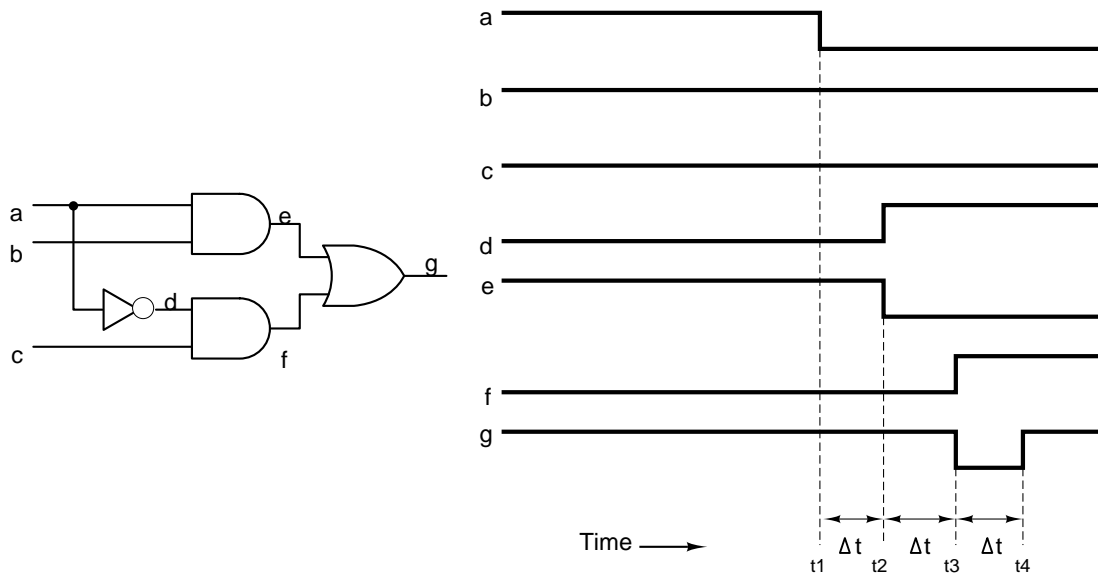
## ▶ Static timing analysis

- ▶ Path delays calculated from primitive models
- ▶ Determine max operating frequency by finding “critical path”  
= longest delay between successive flip flops



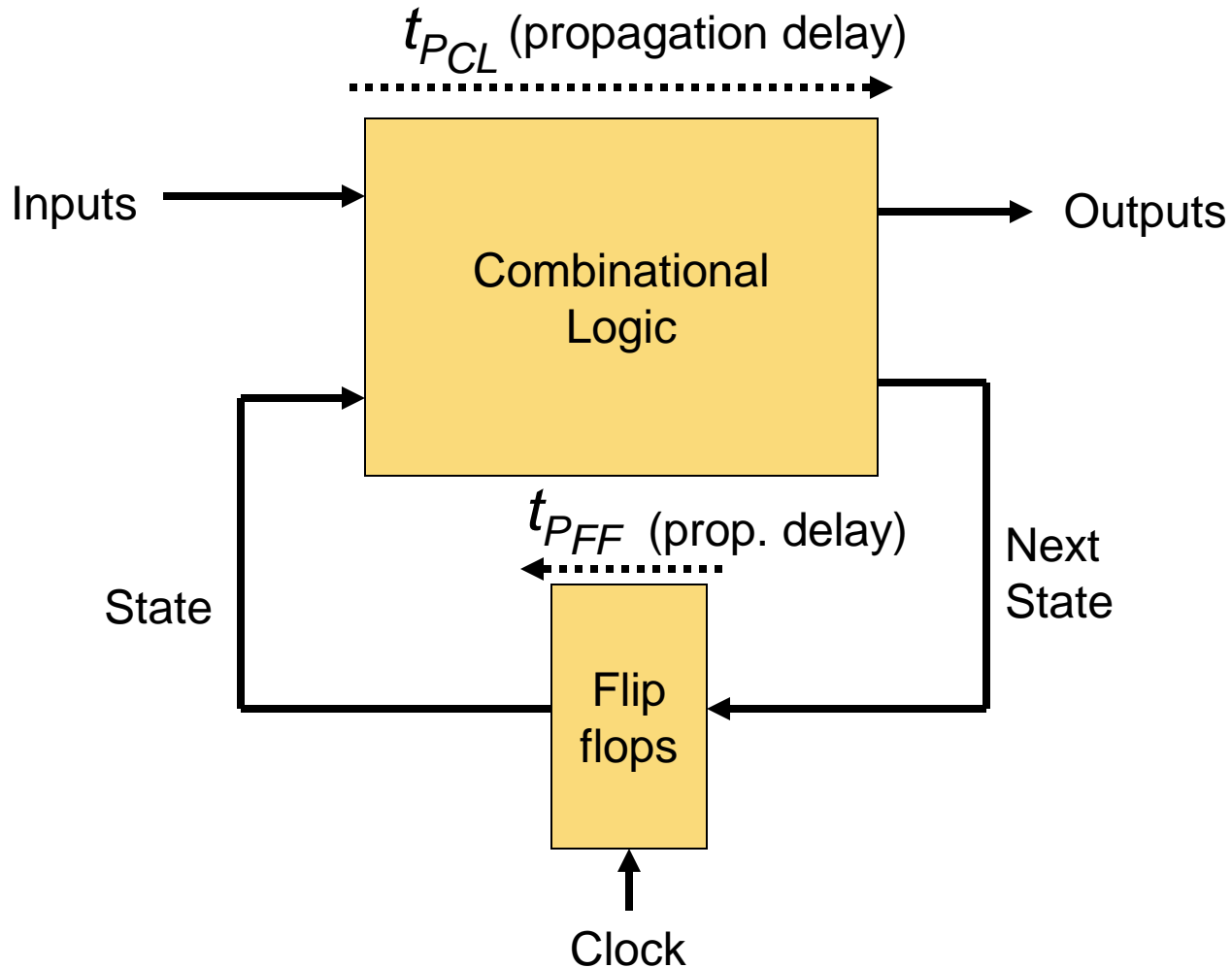
# Detection of static hazards

- ▶ A glitch in  $g$  at time  $t_3$  can be detected from the output waveforms.
- ▶ This occurs because both  $e$  and  $f$  become 0 momentarily between  $t_2$  and  $t_3$ .

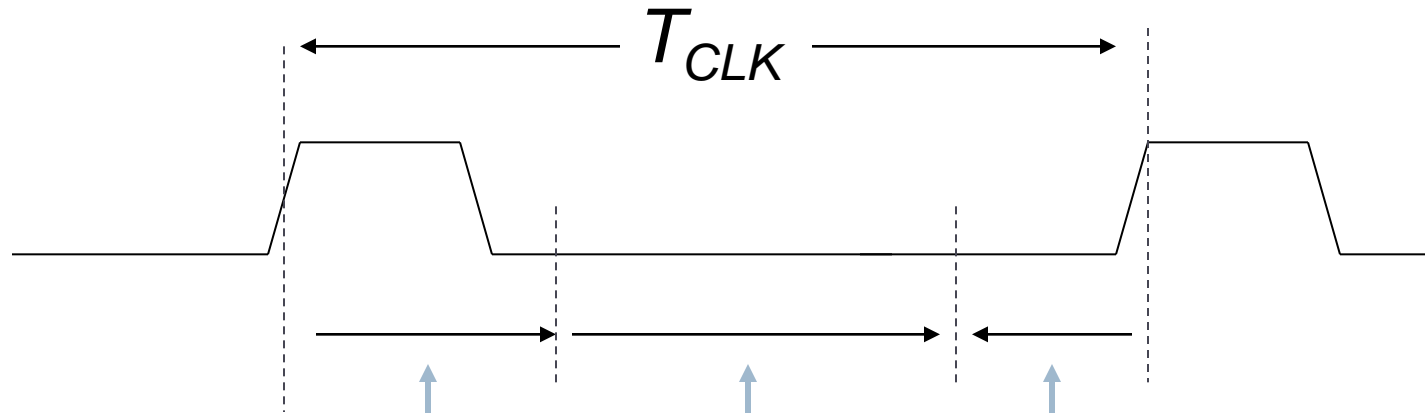


# Circuit-level timing constraints

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# Minimum clock period



$$T_{CLK \text{ min}} = t_{P_{FF}} + t_{P_{CL}} + t_{su}$$

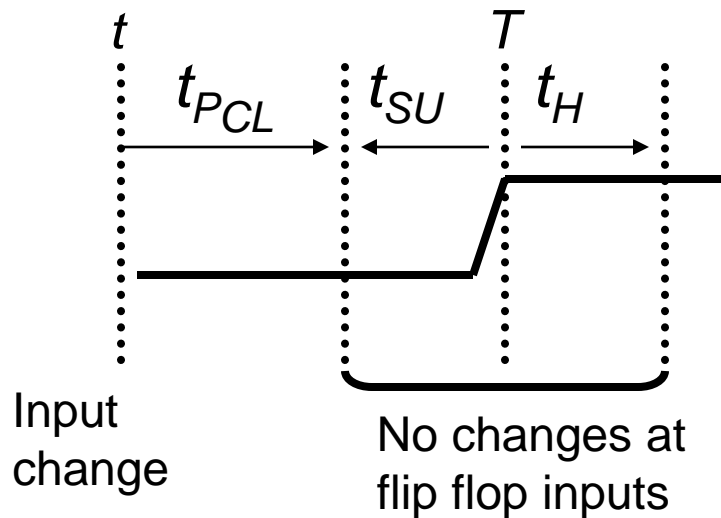
Flip flop  
propagation  
delay (max)

Combinational  
logic propagation  
delay (max)

Flip flop  
setup time



# External input setup/hold times



$t_{PCL}$  = max, propagation delay from ext. signal to FF inputs

$t_{SU}$  = flip flop setup time

$t_H$  = flip flop hold time

$T$  = time of clock transition

$t$  = time of input change ( $\Delta x$ )

For reliable operation, constrain time  $t$  of external input changes, relative to the time  $T$  of the active clock transition:

$$\Delta x : t < T - t_{PCL} - t_{su} \quad \leftarrow \text{Satisfy setup time constraint}$$

$$\Delta x : t > T + t_H - t_{PCL} \quad \leftarrow \text{Satisfy hold time constraint}$$